FAIRCHILD SEMICONDUCTOR

FDS2070N3 150V N-Channel PowerTrench^o MOSFET

General Description

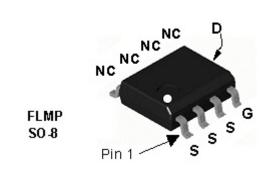
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low $R_{DS(ON)}$ in a small package.

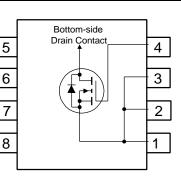
Applications

- Synchronous rectifier
- DC/DC converter

Features

- 4.1 A, 150 V. $R_{DS(ON)} = 78 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 88 \text{ m}\Omega @ V_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability
- Fast switching, low gate charge (38nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

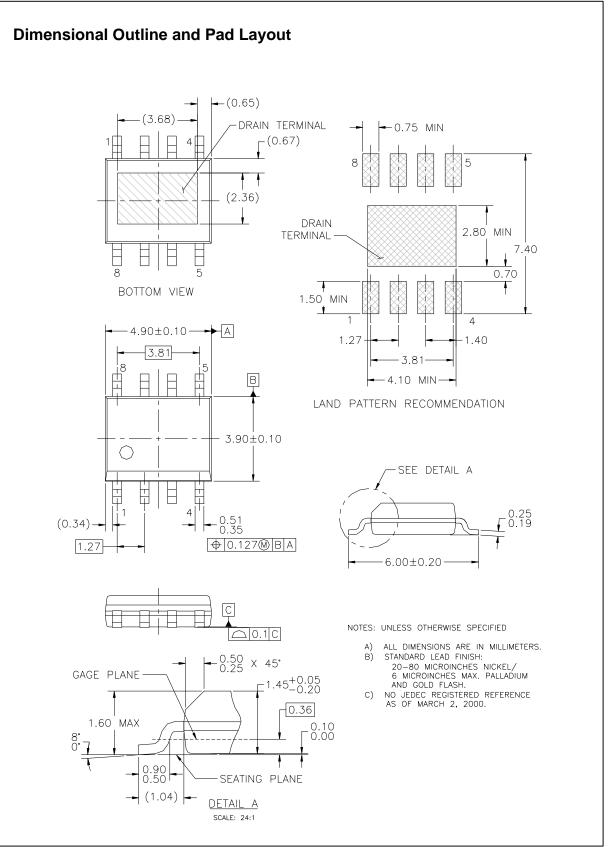
Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain-Source	ce Voltage	150	V		
V _{GSS}	Gate-Sourc	e Voltage	± 20	V		
I _D	Drain Current – Continuous		(Note 1a)	4.1	A	
		- Pulsed		30		
P _D	Power Dissipation for Single Operation		n (Note 1a)	3.0	W	
			(Note 1b)	1.8		
T _J , T _{STG}	Operating a	nd Storage Junction Temp	-55 to +150	°C		
Therma	I Charac	teristics				
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)		ient (Note 1a)	40	°C/W	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)			0.5		
Packag	e Markin	g and Ordering I	nformation			
Device Marking		Device	Reel Size	Tape width	Quantity	
FDS2070N3		FDS2070N3	13"	12mm	2500 units	

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ce Avalanche Ratings		Min	Тур	Max	Units
ce Avalanche Ratings					
Orain-Source Avalanche Energy	Single Pulse, V_{DD} = 150 V, I_D = 10 A L = 8.8 mH			440	mJ
Drain-Source Avalanche Current				10	Α
teristics					
Orain–Source Breakdown /oltage	$V_{GS}=0~V, \qquad I_D=250~\mu A$	150			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A$, Referenced to $25^{\circ}C$		154		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = 120 V, V_{GS} = 0 V$			1	μΑ
Gate-Body Leakage	$V_{GS}=\pm~20~V,~V_{DS}=0~V$			±100	nA
teristics (Note 2)					
Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2	2.6	4	V
Gate Threshold Voltage	$I_D = 250 \ \mu$ A, Referenced to 25°C		-7		mV/°C
Static Drain–Source Dn–Resistance	$ \begin{array}{l} V_{GS} = 10 \; V, I_D = 4.1 \; A \\ V_{GS} = 6.0 V, I_D = 3.8 \; A \\ V_{GS} = 10 \; V, I_D = 4.1 \; A, T_J = 125^\circ C \end{array} $		58 61 112	78 88 160	mΩ
orward Transconductance	$V_{DS} = 10 \text{ V}, I_D = 4.1 \text{ A}$		24		S
haracteristics					
	$V_{DS} = 75 V, V_{GS} = 0 V,$		1884	[pF
	f = 1.0 MHz		102		, pF
					pF
•	$V_{cs} = 15 \text{ mV}$. f = 1.0 MHz				Ω
	$V_{DD} = 75 V_{c}$ $I_{D} = 1 A_{c}$		10	20	ns
	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	-	-		
		-	-		ns
,			-		ns
	$V_{pq} = 75 V_{pq} = 4.1 A_{pq}$				ns nC
	$V_{GS} = 10 V$			53	-
					nC
			1.1		nC
rce Diode Characteristics	and Maximum Ratings				
				2.5	A
/oltage	$V_{GS} = 0 V$, $I_S = 2.5 A$ (Note 2)			1.2	V
,	$I_{\rm F} = 4.1 {\rm A}$				nS
biode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu\text{S} $ (Note 2)		404		nC
	teristics prain–Source Breakdown Voltage preakdown Voltage Temperature Coefficient tero Gate Voltage Drain Current Gate–Body Leakage teristics (Note 2) Gate Threshold Voltage emperature Coefficient Static Drain–Source Dn–Resistance Forward Transconductance haracteristics nput Capacitance Dutput Capacitance Characteristics (Note 2) furn–On Delay Time furn–Off Delay Time furn–Off Fall Time fortal Gate Charge Gate–Drain Charge Tec Diode Characteristics Maximum Continuous Drain–Source Data Fall Fortal Statics Maximum Continuous Drain–Source Data Fall Statics Maximum Continuous Drain–Source Data Fortal Statics Data Fortal Statics Data Fortal Statics Data Fortal Statics Data Fortal Statics Data Fortal Statics Dat	teristicsVarian-Source Breakdown $V_{GS} = 0 \text{ V}$, $I_D = 250 \ \mu\text{A}$ Varian-Source Breakdown Voltage Temperature $I_D = 250 \ \mu\text{A}$, Referenced to 25°C Coefficient $I_D = 250 \ \mu\text{A}$, Referenced to 25°C Coefficient $V_{DS} = 120 \ \text{V}$, $V_{GS} = 0 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\text{V}$ Um-Off Fall Time $V_{CS} = 10 \ \text{V}$ Cate-Source Charge $V_{CS} = 10 \ \text{V}$ Cate-Drain Charge $V_{CS} = 0 \ \text{V}$, $I_S = 2.5 \ \text{A}$ (Note 2)Characteristics Recovery Time $V_{CS} = 0 \ \text{V}$, $I_S = 2.5 \ \text{A}$ (Note 2)	teristicsVGS = 0 V, ID = 250 μ A150InteristicsID = 250 μ A, Referenced to 25°CCoefficientVDS = 120 V, VDS = 0 Vteristics (Note 2)CoefficientCoefficientVDS = VGS, ID = 250 μ ACoefficientCoefficientCoefficientVDS = VGS, ID = 250 μ ACoefficientCoefficientVDS = VGS, ID = 250 μ ACoefficientCoefficientCoefficientVDS = VGS, ID = 250 μ ACoefficientCoefficientVDS = VGS, ID = 250 μ ACoefficientCoefficientCoefficientVDS = 10 V, ID = 4.1 AND CoefficientVDS = 75 V, VGS = 0 V, ID = 4.1 ACoefficientCoefficientVDS = 75 V, VGS = 0 V, ID = 4.1 AMHZCoefficientVDS = 75 V, VGS = 0 V, ID = 1.0 MHZCoefficientVDS = 75 V, ID = 1.0 MHZCoefficientCoefficientVDS = 75 V, ID = 1.4,VDS = 10 V, RGEN = 6 Ω CoefficientCoefficient	teristicsJorain–Source Breakdown 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$V_{GS} = 15 \ mV$, $f = 1.0 \ mHz$ 102Joutput Capacitance $V_{GS} = 15 \ mV$, $f = 1.0 \ mHz$ 10Jurn–On Rise Time $V_{GS} = 10 \ V$, $R_{GEN} = 6 \ \Omega$ 6Jurn–On Rise Time $V_{GS} = 10 \ V$ 8Jate–Source Charge $V_{GS} = 10 \ V$ 8Jate–Source Charge $I_D \ V_{GS} = 10 \ V$ 8	teristicstrain-Source Breakdown foltage $V_{GS} = 0$ V, $I_D = 250$ µA150154irreakdown Voltage Temperature tooefficient $I_D = 250$ µA, Referenced to 25°C154coefficient $I_D = 250$ µA, Referenced to 25°C154sate-Body Leakage $V_{GS} = 120$ V, $V_{GS} = 0$ V1treakdown Voltage Drain Current $V_{GS} = 120$ V, $V_{GS} = 0$ V1treakdown Voltage $V_{GS} = 120$ V, $V_{DS} = 0$ V±100teristics (Note 2)Sate Threshold Voltage $I_D = 250$ µA, Referenced to 25°C-7colspan="2">emperature Coefficienttraitic Drain-Source $V_{GS} = 10$ V, $I_D = 4.1$ A58On-Resistance $V_{GS} = 10$ V, $I_D = 4.1$ A24haracteristicsonward Transconductance $V_{DS} = 75$ V, $V_{GS} = 0$ V,1884Duput CapacitanceSate Resistance $V_{GS} = 10$ V, $I_D = 4.1$ 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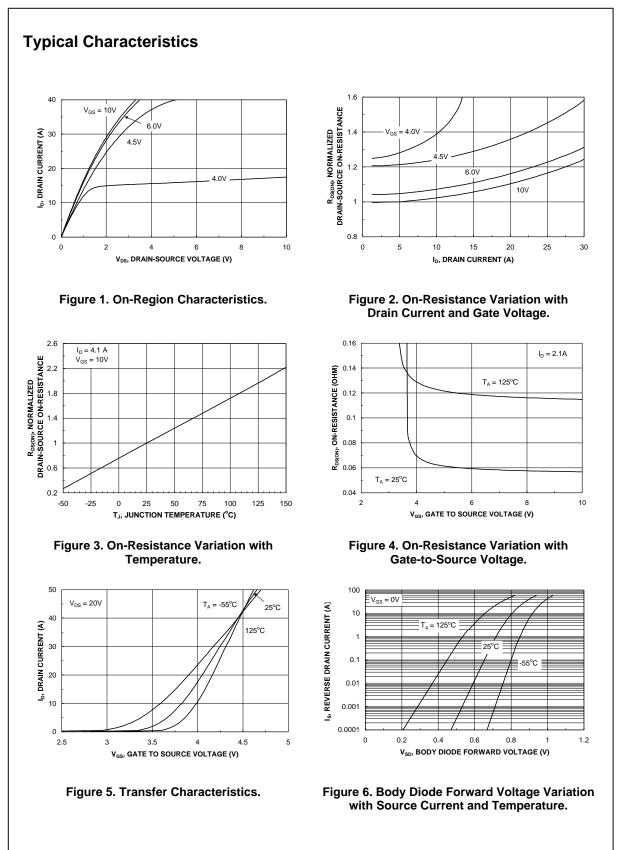
Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

FDS2070N3

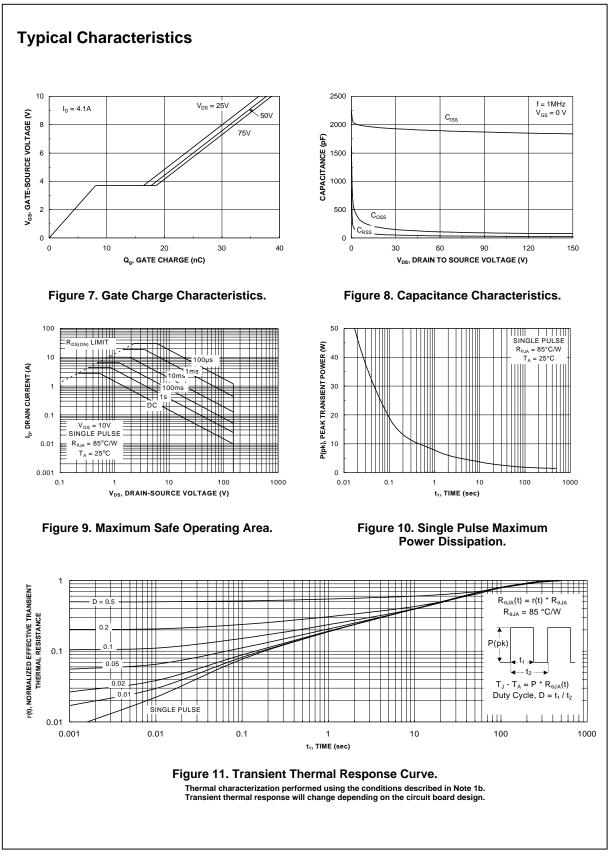


FDS2070N3

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